

**METHOD, APPARATUS, AND COMPUTER PROGRAM PRODUCT FOR
IMPLEMENTING DETERMINISTIC BASED BROKEN SCAN CHAIN
DIAGNOSTICS**

Abstract of the Disclosure

- 5 A method, apparatus and computer program product are provided for
implementing deterministic based broken scan chain diagnostics. A
deterministic test pattern is generated and is loaded into each scan chain in
the device under test using lateral insertion via system data ports applying
system clocks. Then each scan chain is unloaded and a last switching latch
10 is identified. The testing steps are repeated a selected number of times.
Then checking for consistent results is performed. When consistent results
are identified, then the identified last switching latch is sent to a Physical
Failure Analysis system.